High input impedance Front-End Circuit

```
M.Pyée<sup>(1)</sup>, J.L. Michau<sup>(1)</sup>, T. Hachemi<sup>(1)</sup>, J.G. Trotignon<sup>(1)</sup>, S. Bart<sup>(2)</sup>, P. Picard<sup>(2)</sup>, P. E.Vert<sup>(2)</sup>
```

(1)LPCE . CNRS, UMR-6115 , 3A Avenue de la Recherche Scientifique 45071 ORLEANS CEDEX 2 . France mpyee@cnrs-orleans.fr, jlmichau@cnrs-orleans.fr, thachemi@cnrs-orleans.fr, jqtrotiq@cnrs-orleans.fr, orleans.fr,

(2) Station de radioastronomie de Nançay 18330 NANCAY . France Severin.Bart@obs-nancay.fr, Philippe.Picard@obs-nancay.fr, PE.Vert@obs-nancay.fr,

We present a front-end circuit for a sensor with a high input impedance. The voltage gain of this circuit is not critical (GV = 10 is sufficient), but other parameters like the input impedance, the input capacitance, the bandwidth and the power consumption are imperatives. The necessary principal characteristics are reported below:

- . high input impedance (higher than 30 M @ 1KHz)
- a low input capacitance (< 1.5 pF)
- low power consumption (about 30 mW)
- · a bandwidth higher than 50 MHz
- an input noise lower than 30 nV/sqrt(Hz)@1MHz
- 2V of output dynamics

a rad-hard behaviour.

- the characteristics must be stable between +100 and -100°C
- the final circuit will have to be rad-hard (this will be carried out in the final version of the circuit) Several tests for the design were tested (in particular a version containing transistors MOS) and finally the selected architecture is a bipolar structure for which the characteristics, after foundry, are very close to the desired values. The first stage comprises a whole of four sub-stages with high input impedance. Each sub-stage has also a high output impedance which is gradually decreased until being able to drive a gain stage which constitutes the second stage of the circuit. The last stage is an output stage which allows an adaptation of impedance on 600 Ω . The most delicate part of this circuit is the first stage. It is not indeed common to have a bipolar structure with so high input impedance. With the MOS structures, which we tested, it was not possible to obtain a low input capacitance, associated with a large bandwidth and low power consumption and low input noise. The first realization, intended to test the characteristics of the circuit,

was carried out on silicon with a technology of 0.8 µm. The final structure will use the same architecture, but with a substrate allowing